

**N-CHANNEL MOS FIELD EFFECT TRANSISTOR  
FOR SWITCHING**

**DESCRIPTION**

The  $\mu$ PA1873 is a switching device which can be driven directly by a 2.5 V power source.

This device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

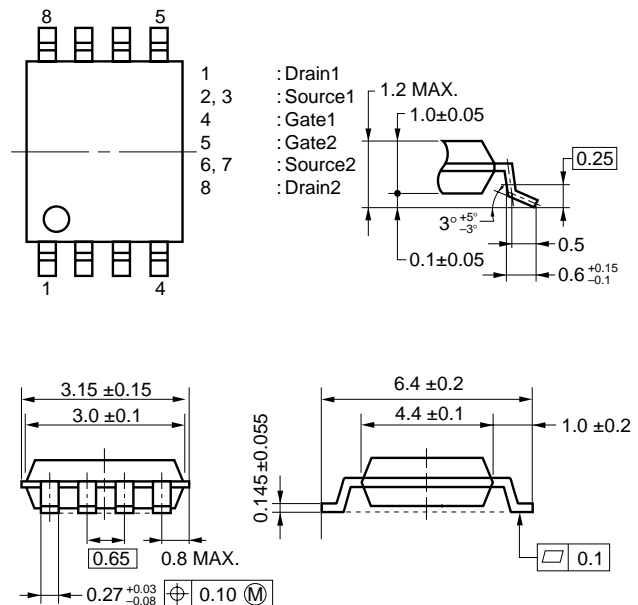
**FEATURES**

- 2.5 V drive available
- Low on-state resistance  
 $R_{DS(on)1} = 23.0 \text{ m}\Omega \text{ MAX. (} V_{GS} = 4.5 \text{ V, } I_D = 3.0 \text{ A)}$   
 $R_{DS(on)2} = 24.0 \text{ m}\Omega \text{ MAX. (} V_{GS} = 4.0 \text{ V, } I_D = 3.0 \text{ A)}$   
 $R_{DS(on)3} = 28.0 \text{ m}\Omega \text{ MAX. (} V_{GS} = 3.1 \text{ V, } I_D = 3.0 \text{ A)}$   
 $R_{DS(on)4} = 29.0 \text{ m}\Omega \text{ MAX. (} V_{GS} = 2.5 \text{ V, } I_D = 3.0 \text{ A)}$
- Built-in G-S protection diode against ESD

**ORDERING INFORMATION**

PART NUMBER	PACKAGE
$\mu$ PA1873GR-9JG	Power TSSOP8

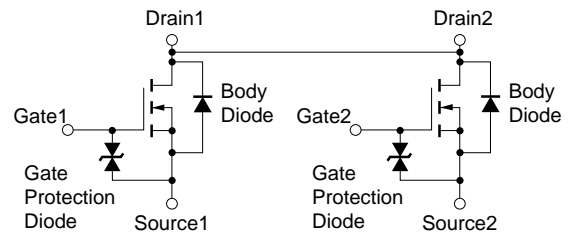
**PACKAGE DRAWING (Unit : mm)**



**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25°C)**

Drain to Source Voltage (V <sub>GS</sub> = 0 V)	V <sub>DSS</sub>	20	V
Gate to Source Voltage (V <sub>DS</sub> = 0 V)	V <sub>GSS</sub>	±12	V
Drain Current (DC) (T <sub>A</sub> = 25°C)	I <sub>D(DC)</sub>	±6.0	A
Drain Current (pulse) <sup>Note1</sup>	I <sub>D(pulse)</sub>	±80	A
Total Power Dissipation (2 unit) <sup>Note2</sup>	P <sub>T</sub>	2.0	W
Channel Temperature	T <sub>ch</sub>	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C

**EQUIVALENT CIRCUIT**



- Notes**
1.  $PW \leq 10 \mu s$ , Duty Cycle  $\leq 1\%$
  2. Mounted on ceramic substrate of  $5000 \text{ mm}^2 \times 1.1 \text{ mm}$

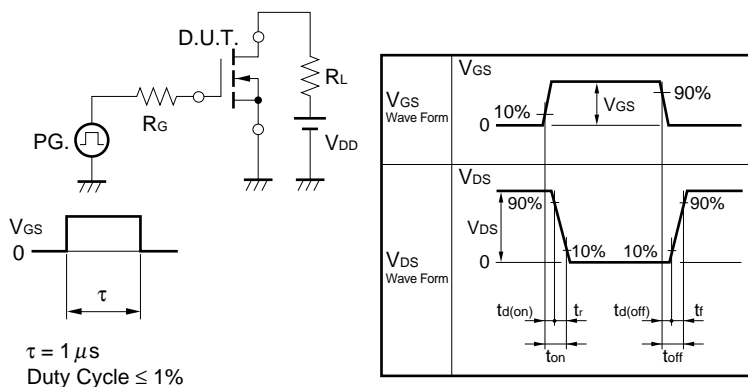
**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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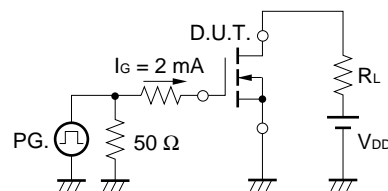
**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25°C)**

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			10	μA
Gate Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±12 V, V <sub>DS</sub> = 0 V			±10	μA
Gate Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1.0 mA	0.5	1.0	1.5	V
Forward Transfer Admittance	y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 3.0 A	5.0			S
Drain to Source On-state Resistance	R <sub>DS(on)1</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 3.0 A	13.0	18.0	23.0	mΩ
	R <sub>DS(on)2</sub>	V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 3.0 A	14.0	19.0	24.0	mΩ
	R <sub>DS(on)3</sub>	V <sub>GS</sub> = 3.1 V, I <sub>D</sub> = 3.0 A	14.5	21.5	28.0	mΩ
	R <sub>DS(on)4</sub>	V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 3.0 A	15.0	24.5	29.0	mΩ
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 10 V		705		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V		205		pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz		145		pF
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 3.0 A		60		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.0 V		310		ns
Turn-off Delay Time	t <sub>d(off)</sub>	R <sub>G</sub> = 10 Ω		380		ns
Fall Time	t <sub>f</sub>			420		ns
Total Gate Charge	Q <sub>G</sub>	V <sub>DD</sub> = 16 V		9.0		nC
Gate to Source Charge	Q <sub>GS</sub>	V <sub>GS</sub> = 4.0 V		2.0		nC
Gate to Drain Charge	Q <sub>GD</sub>	I <sub>D</sub> = 6.0 A		4.0		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 6.0 A, V <sub>GS</sub> = 0 V		0.84		V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 6.0 A, V <sub>GS</sub> = 0 V		480		ns
Reverse Recovery Charge	Q <sub>rr</sub>	di/dt = 50 A / μs		1200		nC

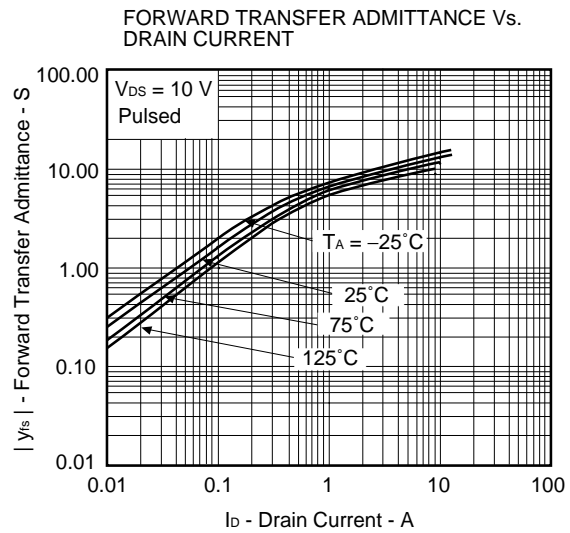
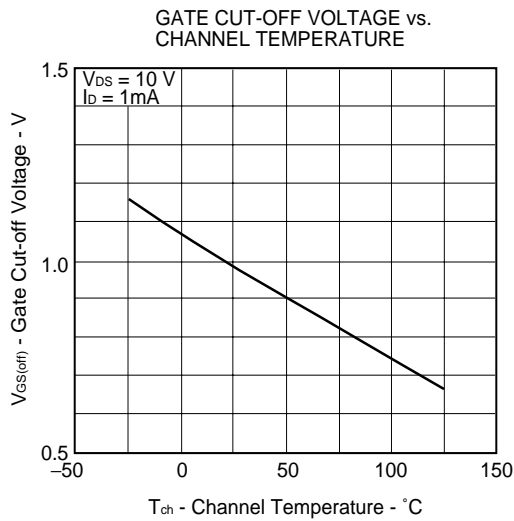
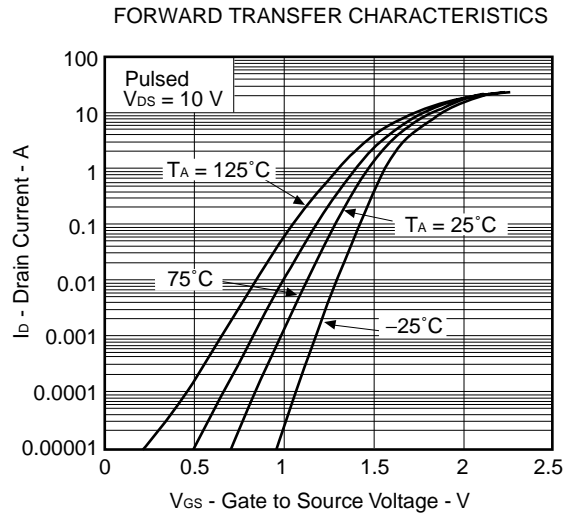
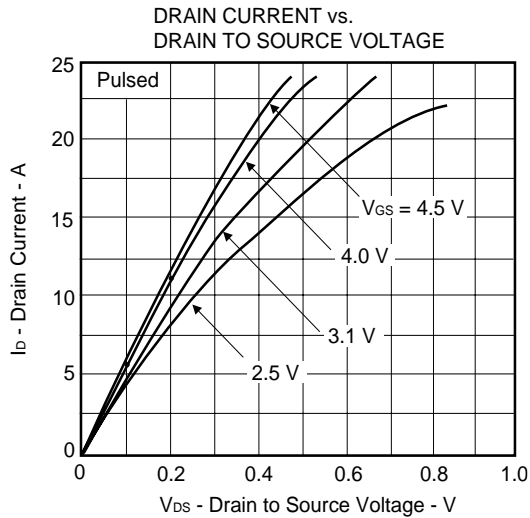
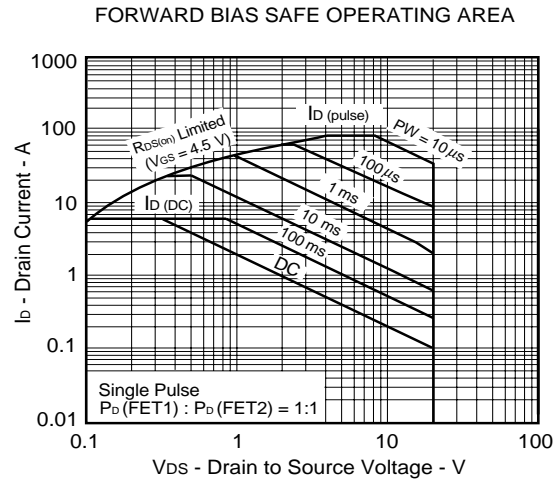
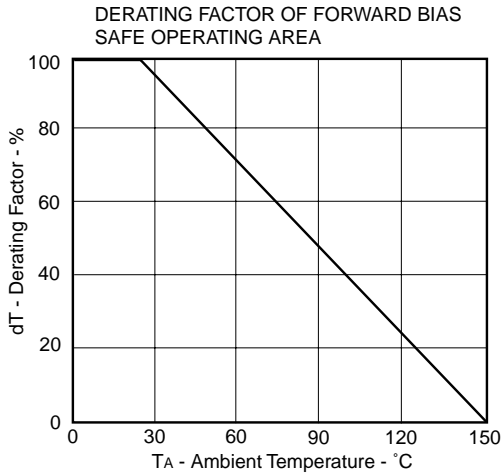
**TEST CIRCUIT 1 SWITCHING TIME**

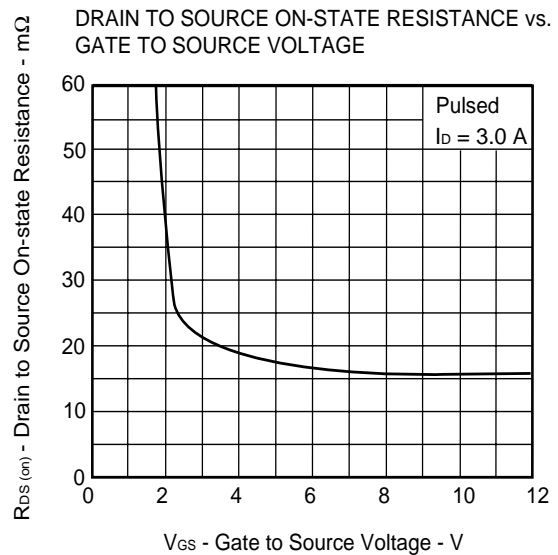
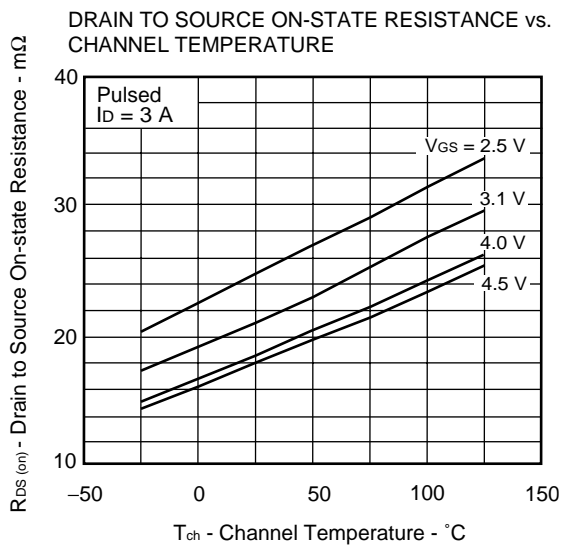
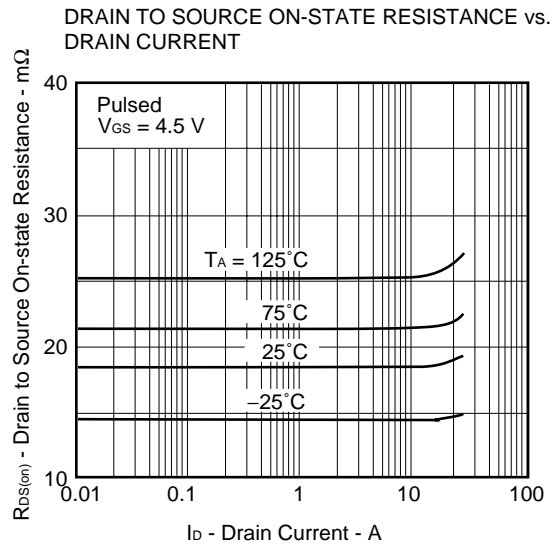
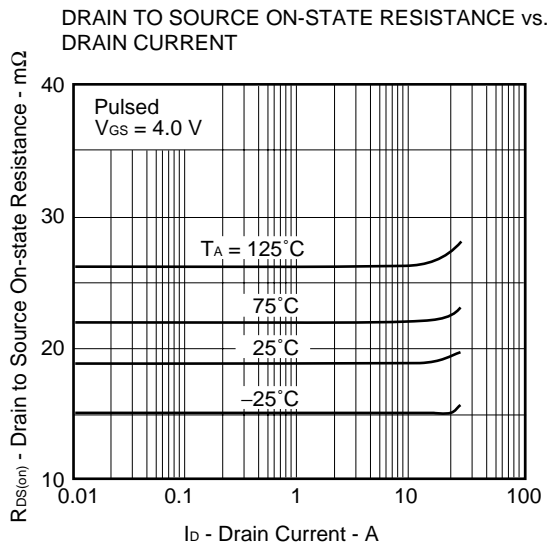
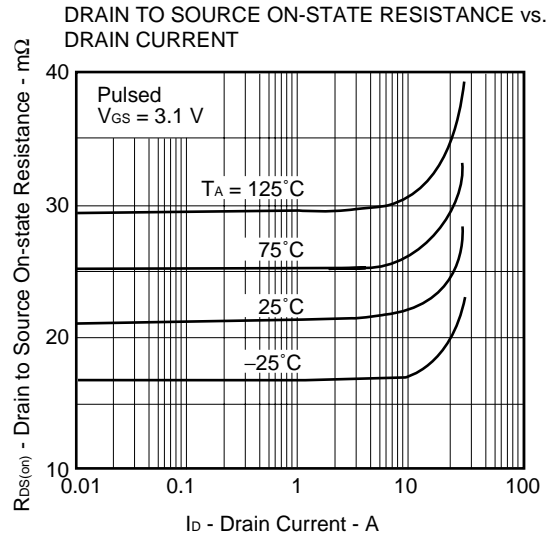
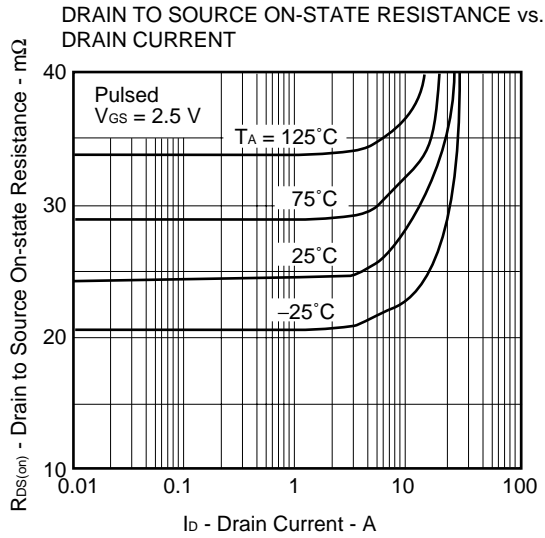


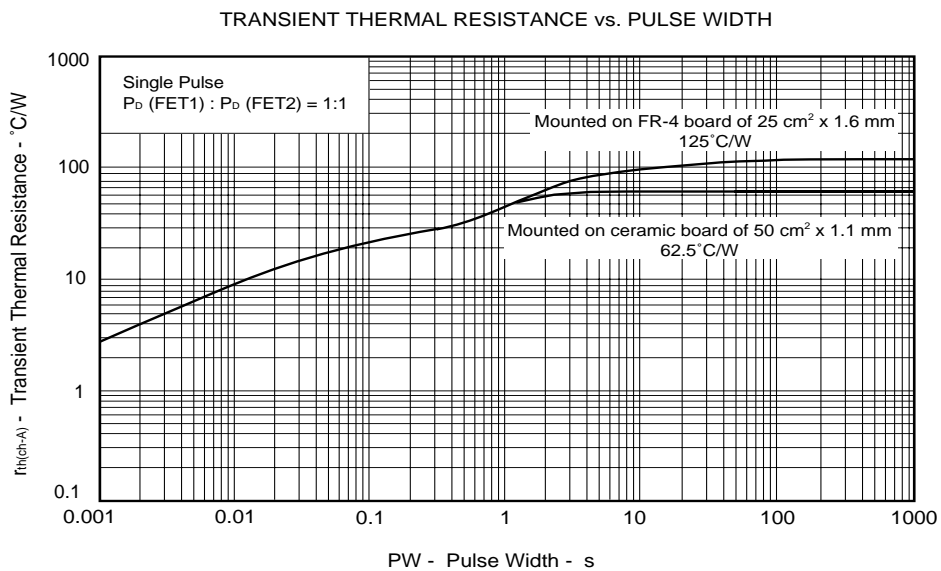
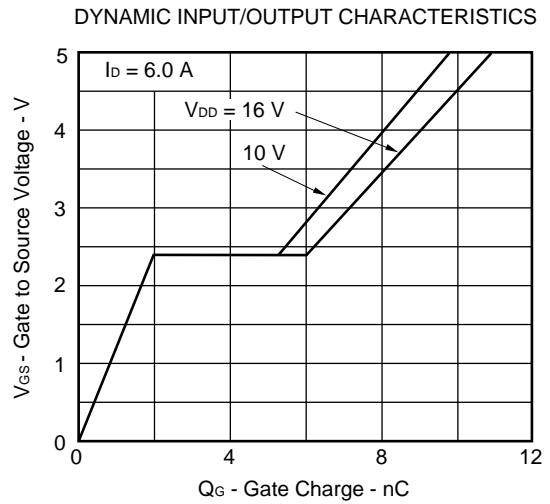
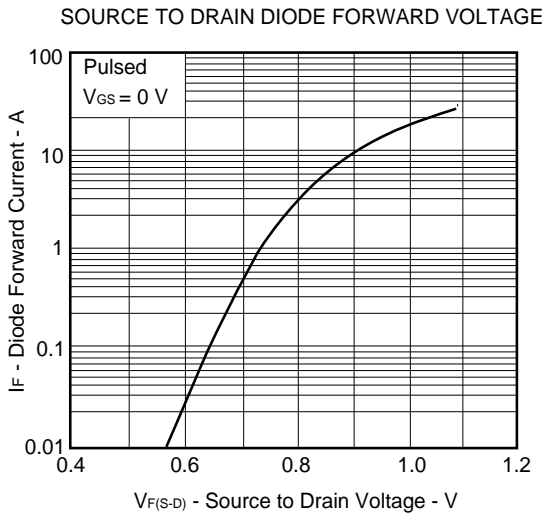
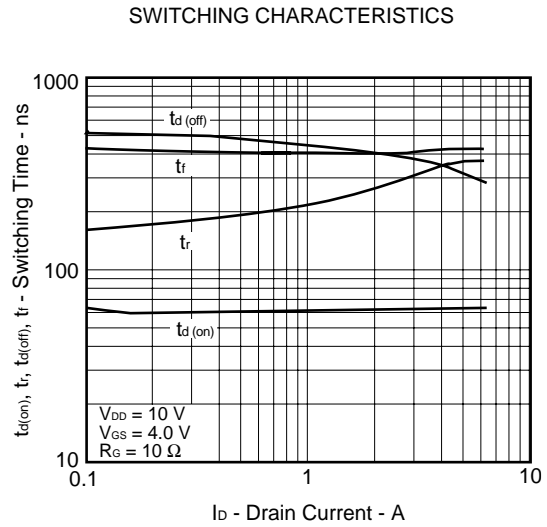
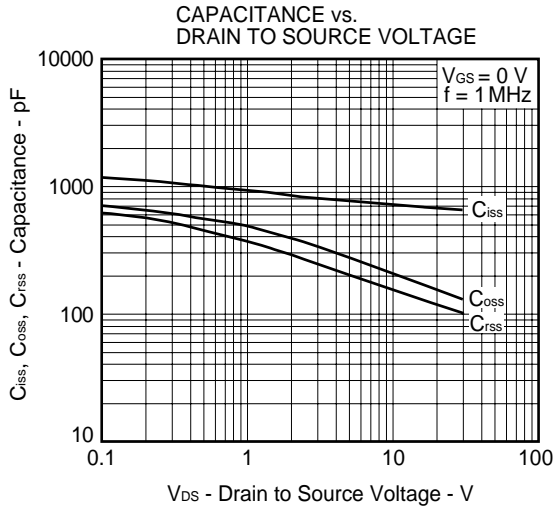
**TEST CIRCUIT 2 GATE CHARGE**



TYPICAL CHARACTERISTICS (T<sub>A</sub> = 25°C)







[MEMO]

[MEMO]

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